

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Mehrdad Nikoonahad et al.
Title: Optical System For Measuring Samples Using Short Wavelength Radiation
Application No.: 10/718,126 Filing Date: November 19, 2003
Examiner: Pham, Hoa Q. Group Art Unit: 2886
Docket No.: TNCR.197US1 Conf. No.: 9108

Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR CONTINUED EXAMINATION (RCE)

Dear Sir:

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application. Please consider the Response to Office Action and Petition for Extension of Time, which are being filed herewith.

The RCE fee of \$790.00 required under 37 C.F.R. § 1.17(e) has been authorized via EFS to Deposit Account 04-0258. The Commissioner is hereby authorized to charge any additional fees, which may be required, or credit any overpayment to Deposit Account 04-0258. Please contact the undersigned with any questions concerning this request or the above-identified patent application.

FILED VIA EFS

Respectfully submitted,



James S. Hsue
Reg. No. 29,545

09/18/2007

Date

DAVIS WRIGHT TREMAINE LLP
505 Montgomery Street, Suite 800
San Francisco, California 94111-6533
Telephone: (415) 276-6500
Facsimile: (415) 276-6599
Email: jameshsue@dwt.com